## CE

## **EMC COMPLIANCE TEST REPORT**

for

#### **Industrial Display Monitor**

Trade Name	: N/A
Model Number	: AMB-220A
<b>Product Family</b>	: OPD-212A
Serial Number	: N/A
<b>Report Number</b>	: 02E9999-E
Date	: March 20, 2002
Regulations	: See below

Standards	Results (Pass/Fail)
EN 55022: 1998	PASS
EN 61000-3-2: 1995+A1: 1998+A2: 1998+A14: 2000	PASS
EN 61000-3-3: 1995	PASS
EN 50024: 1998	PASS
- IEC 61000-4-2: 1995 +A2: 2000	PASS
- IEC 61000-4-3: 1995	PASS
- IEC 61000-4-4: 1995	PASS
- IEC 61000-4-5: 1995	PASS
- IEC 61000-4-6: 1996	PASS
- IEC 61000-4-8: 1993	N/A
- IEC 61000-4-11: 1994	PASS

Prepared for :

AAEON Technology Inc. 5F, No. 135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R. O. C.

Prepared by :



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# **CE** EC-Declaration of Conformity

For the following equipment:

Industrial Display Monitor

(Product Name)

AMB-220A; OPD-212A

(Model Designation / Trade name)

AAEON Technology Inc.

(Manufacturer Name)

5F, No. 135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R. O. C.

(Manufacturer Address)

is herewith confirmed to comply with the requirements set out in the Council Directive on the Approximation of the Laws of the Member States relating to Electromagnetic Compatibility Directive (89/336/EEC, Amended by 92/31/EEC, 93/68/EEC & 98/13/EC), For the evaluation regarding the Electromagnetic Compatibility (89/336/EEC, Amended by 92/31/EEC & 93/68/EEC & 98/13/EC ) the following standards are applied:

V	EN 55022	: 1998

*V* EN 61000-3-2: 1995+A1: 1998+A2: 1998+A14: 2000

- V EN 61000-3-3: 1995
- V EN50024: 1998

IEC 61000-4-2: 1995 +A2: 2000, IEC 61000-4-3: 1995, IEC 61000-4-4: 1995

IEC 61000-4-5: 1995, IEC 61000-4-6: 1996, IEC 61000-4-11: 1994

The following manufacturer / importer or authorized representative established within the EUT is responsible for this declaration:

( Company Name )

(Company Address)

Person responsible for making this declaration:

(Name, Surname)

(Position / Title)

(Place)

(Date)

(Legal Signature)

## TABLE OF CONTENTS

DESCRIPTION	PAGE
VERIFICATION OF COMPLIANCE	5
GENERAL INFORMATION	6
SYSTRM DESCRIPTION	7
PRODUCT INFORMATION	8
SUPPORT EQUIPMENT	9
TEST FACILITY	10
TEST EQUIPMENT	11
SECTION 1 EN 55022(LINE CONDUCTED & RADIATED EMISSION)	14
MEASUREMENT PROCEDURE & LIMIT (LINE CONDUCTED EMISSION TEST)	14
MEASUREMENT PROCEDURE & LIMIT (RADIATED EMISSION TEST)	17
BLOCK DIAGRAM OF TEST SETUP	19
SUMMARY DATA	20
SECTION 2 EN61000-3-2 & EN 61000-3-3 (POWER HARMONICS	22
& VOLTAGE FLUCTUATION/FLICKER)	
BLOCK DIAGRAM OF TEST SETUP	22
RESULT	22
SECTION 3 IEC 61000-4-2 (ELECTROSTATIC DISCHARGE)	33
BLOCK DIAGRAM OF TEST SETUP	34
TEST PROCEDURE	34
PERFORMANCE & RESULT	38
SECTION 4 IEC 61000-4-3 (RADIATED ELECTROM	38
AGNETIC FIELD)	
BLOCK DIAGRAM OF TEST SETUP	39
TEST PROCEDURE	
PERFORMANCE & RESULT	40

DESCRIPTION	PAGE
SECTION 5 IEC 61000-4-4 (FAST TRANSIENTS/BURST)	41
BLOCK DIAGRAM OF TEST SETUP	41
TEST PROCEDURE	42
PERFORMANCE & RESULT	42
SECTION 6 IEC 61000-4-5 (SURGE IMMUNITY)	43
BLOCK DIAGRAM OF TEST SETUP	43
TEST PROCEDURE	44
PERFORMANCE & RESULT	44
SECTION 7 IEC 61000-4-6 (CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS)	45
BLOCK DIAGRAM OF TEST SETUP	45
TEST PROCEDURE	46
PERFORMANCE & RESULT	47
SECTION 8 IEC 61000-4-8 (Power Frequency Magnetic Field))	48
BLOCK DIAGRAM OF TEST SETUP	48
TEST PROCEDURE	49
PERFORMANCE & RESULT	49
SECTION 9 IEC 61000-4-11 (VOLTAGE DIP/INTERRUPTION	<b>N</b> ) 50
BLOCK DIAGRAM OF TEST SETUP	50
TEST PROCEDURE	51
PERFORMANCE & RESULT	51
APPENDIX 1 PHOTOGRAPHS OF TEST SETUP	52
EN 55022 TEST EN 61000-3-2 TEST EN 61000-3-3 TEST IEC 61000-4-2 Test IEC 61000-4-3 Test IEC 61000-4-4 TEST IEC 61000-4-5 TEST IEC 61000-4-6 TEST IEC 61000-4-11 TEST	
APPENDIX 2 PHOTOGRAPHS OF EUT	62
APPENDIX 3 CONDUCTED EMISSION PLOT & RADIATED	71
EMISSION DATA	

## **VERIFICATION OF COMPLIANCE**

Equipment Under Test:	Industrial Display Monitor
Trade Name:	N/A
Model Number:	AMB-220A
Product Family:	OPD-212A
Serial Number:	N/A
Applicant:	<b>AAEON Technology Inc.</b> 5F, No. 135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R. O. C.
Manufacturer:	<b>AAEON Technology Inc.</b> 5F, No. 135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R. O. C.
Type of Test:	EMC Directive 89/336/EEC for CE Marking
Technical Standards:	EN 55022: 1998 EN 61000-3-2: 1995+A1: 1998+A2: 1998+A14: 2000 EN 61000-3-3: 1995 EN 50024: 1998 (IEC 61000-4-2: 1995 +A2: 2000, IEC 61000-4-3: 1995 IEC 61000-4-4: 1995, IEC 61000-4-5: 1995 IEC 61000-4-6: 1996, IEC 61000-4-11: 1994)
File Number:	02Е9999-Е
Date of test:	March 11, 2002 & March 12, 2002
Deviation:	N/A
Condition of Test Sample:	Normal

The above equipment was tested by C&C Laboratory Co., Ltd. for compliance with the requirements set forth in EMC Directive 89/336/EEC and the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements.

The test results of this report relate only to the tested sample identified in this report.

Approved by Authorized Signatory:

RICK YEO / EMC MANAGER

*Report Number: 02E9999-E March 20, 2002* 

## **GENERAL INFORMATION**

Applicant:	<b>AAEON Technology Inc.</b> 5F, No. 135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R. O. C.
Contact Person:	Milo Wang / Q. E. Dept. Engineer
Manufacturer:	<b>AAEON Technology Inc.</b> 5F, No. 135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R. O. C.
File Number:	02E9999-E
Date of Test:	March 11, 2002 & March 12, 2002
Equipment Under Test:	Industrial Display Monitor
Model Number:	AMB-220A
Product Family:	OPD-212A
Serial Number:	N/A
Type of Test:	EMC Directive 89/336/EEC for CE Marking
Technical Standards:	EN 55022: 1998 EN 61000-3-2: 1995+A1: 1998+A2: 1998+A14: 2000 EN 61000-3-3: 1995 EN 50024: 1998 (IEC 61000-4-2: 1995 +A2: 2000, IEC 61000-4-3: 1995 IEC 61000-4-4: 1995, IEC 61000-4-5: 1995 IEC 61000-4-6: 1996, IEC 61000-4-11: 1994)
Frequency Range (EN 55022):	150kHz to 30MHz for Line Conducted Test 30MHz to 1000MHz for Radiated Emission Test
Test Site	<b>C&amp;C LABORATORY CO., LTD.</b> No. 199, Chung Sheng Road, Hsin Tien City, Taipei Taiwan, R. O. C.

## SYSTEM DESCRIPTION

#### **EUT Test Procedure:**

- 1. Windows 98 Boots System.
- 2. Run Winemc.Exe To Activate All Peripherals And Display "H" Pattern On Monitor Screen.

## **PRODUCT INFORMATION**

Housing Type:	Plastic w/ metal plate
EUT Power Rating:	DC 12V from AC Adaptor
AC power during Test:	230VAC, 50Hz to AC Adaptor
AC Adaptor Manufacturer:	EDAC
AC Adaptor Model Number:	EA1050C
AC Power Cord Type:	Unshielded, 1.8m (Detachable)
DC Power Cable Type:	Shielded, 1.2m (Non-Detachable, with a ferrite core)
EUT I/O Cable (DB 9):	Shielded, 1.8m (Detachable)
EUT I/O Cable (DB 15):	Shielded, 1.2m (Detachable , with two ferrite cores)
OSC/Clock Frequencies :	Y1= 14.318MHz; Q7= 24.576MHz; Y2= 14.318MHz
A/D Board Model:	TB-86-1
LVDS Board Model:	TB-903A
LCD Panel Brand / Model Number:	Toshiba 12.1" / LTM12C289

#### Model Difference:

Model Name	Differences	Tested (Checked)
AMB-220A	Original Model	$\boxtimes$
OPD-212A	Additional Model (Without the Case)	

#### I/O Port of EUT:

I/O PORT TYPES	Q' TY	TESTED WITH
1). Serial Port (DB 9)	1	1
2). VGA Port (DB15)	1	1
3). Video (RCA)	1	1

#### Note: N/A

No	Equipment	Model #	Serial #	FCC ID	Trade Name	Data Cable	Power Cord
1.	PS/2 Mouse	M-S34	LZE12352345	DZL211029	LOGITECH	Shielded, 1.9m	N/A
2.	Printer	2225C	2550540697	BS46XU2225C	HP	Shielded, 1.8 m	Unshielded, 1.8m
3.	Notebook	PS181L	N/A	DoC	TOSHIBA	DB9: Shielded, 1.8m DB15: Shielded, 1.2m With two ferrite cores RCA: Unshielded, 1.8m	Unshielded, 1.8m

## SUPPORT EQUIPMENT

**Note:** All the above equipment/cables were placed in worse case positions to maximize emission signals.

**Grounding:** Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

## **TEST FACILITY**

Location:	No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R. O. C.
Description:	There are two 3/10m open area test sites and one line conducted lab for final test. The Open Area Test Sites and the Line Conducted labs are constructed and calibrated to meet the FCC requirements in documents ANSI C63.4: 1992 and CISPR 22/EN 55022 requirements.
Site Filing:	A site description is on file with the Federal Communications Commission, 7435 Oakland Mills Road, Columbia, MD 21046.
	Registration also was made with Voluntary Control Council for Interference (VCCI).
Site Accreditation:	Accredited by A2LA (Certificate #: 824.01) for EMC.
	Also accredited by BSMI for the product category of Information Technology Equipment.
Instrument Tolerance:	All measuring equipment is in accord with ANSI C63.4 and CISPR 22 requirements that meet industry regulatory agency and accreditation agency requirement.

**Ground Plane:** Two conductive reference ground planes were used during the Line Conducted Emission, one in vertical and the other in horizontal. The dimensions of these ground planes are as below. The vertical ground plane was placed distancing 40 cm to the rear of the wooden test table on where the EUT and the support equipment were placed during test. The horizontal ground plane projected 50 cm beyond the footprint of the EUT system and distanced 80 cm to the wooden test table. For Radiated Emission Test, one horizontal conductive ground plane extended at least 1m beyond the periphery of the EUT and the largest measuring antenna, and covered the entire area between the EUT and the antenna. It has no holes or gaps having longitudinal dimensions larger than one-tenth of a wavelength at the highest frequency of measurement up to 1GHz.

## **TEST EQUIPMENT LIST (EMISSION)**

**Instrumentation:** The following list contains equipment used at C & C Laboratory, Co., Ltd. for testing. The equipment conforms to the CISPR 16-1 / ANSI C63.2-1988 Specifications for Electromagnetic Interference and Field Strength Instrumentation from 9kHz to 1.0 / 2.0 GHz.

#### Equipment used during the tests:

• • • • • • • • • • • • • • • • • • • •					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
EMI TEST DISPLAY	R&S	DSAI-D 804.8932.52	827832/001	10/29/01	10/28/02
EMI TEST RF UNIT	R&S	ESBI-RF/1005.4300.52	827832/003	10/29/01	10/28/02
AMPLIFIER	HP	8447DB	1644A02328	05/07/01	05/06/02
ANTENNA	SCHWARZBECK	VULB 9160	3104	05/17/01	05/16/02
CABLE	TIME MICROWAVE	LMR-400	N-TYPE02	07/09/01	07/08/02

**Open Area Test Site:** #D

Conducted Emission Test Site: Conducted Room

EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
TEST RECEIVER	R&S	ESHS20	840455/006	03/15/01	03/14/02
LISN	SOLAR	8012-50-R-24-BNC	8305114	07/23/01	07/22/02
LISN(EUT)	EMCO	3825/2	1435	01/16/02	01/15/03

The calibrations of the measuring instruments, including any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.

### **TEST EQUIPMENT LIST**

#### For Power Harmonic & Voltage Fluctuation/Flicker Measurement:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HP / Harmonic & Flicker Tester	6842A	3531A-000142	06/15/2001	06/14/2002

#### For ESD test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
S.G. / ESD Simulator	SESD 2000	812006	02/08/2002	02/07/2003

#### For Radiated Electromagnetic Field immunity Measurement:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
R&S / Signal Generator	SMY 02	DE13751	01/10/2002	01/09/2003
IFI /	EFS-5	713-0695	06/29/2001	06/28/2002
"E" Field sensor/ Light				
Modulator Transmitter				
IFI / Combination Amplifier	SMX100	2067-1196	06/28/2001	06/27/2002
IFI / Leveling Pre-Amplifier	LPA-5B	714-0695	05/01/2001	04/30/2002
EMCO / Biconilog Antenna	3142	9609-1087	No Calibration	No Calibration
			Required	Required

#### For Fast Transients/Burst test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
KeyTek Instruments /	E421	9502326	11/01/2001	10/31/2002
EFT Generator				
KeyTek Instruments /	CCL-4	9503290	No Calibration	No Calibration
Capacitive Clamp			Required	Required
HAEFELY TRENCH /				
Fast Transients/Burst	PEFT- JUNIOR	583 333-117	08/21/2001	08/20/2002
Generator				
HAEFELY TRENCH /	093 506.1	080 421.13	N/A	N/A
Clamp	095 500.1	000 421.13	1N/PA	1 N/ P <b>1</b>

#### For Surge Immunity test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
Surger Generator	E501	9502324	11/01/2001	10/31/2002
KeyTek Instruments				
Telecom Lines Coupler	CM-TELCD	0104399	05/01/2001	04/30/2002
DECOUPLER				
KeyTek Instruments				
I/O Signal Line	CM-I/OCD	0103234	05/01/2001	04/30/2002
DECOUPLER				
KeyTek Instruments				
HAEFELY TRENCH /	PSUGER 4010	583 334-71	09/01/2001	08/31/2002
Surge Tester	FSUGER 4010	363 334-71	09/01/2001	06/31/2002

#### For CS test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
R&S / Signal Generator	SMY 02	DE13751	01/10/2002	01/09/2003
IFI / Combination Amplifier	SMX100	2067-1196	06/28/2001	06/27/2002
IFI / Leveling Pre-Amplifier	LPA-5B	714-0695	05/01/2001	04/30/2002
FISCHER /	FCC-801-M3-16A	99122	10/27/2001	10/26/2002
Power Line Coupling				
Decoupling Network				
FISCHER /	F-120-9B	54	10/30/2001	10/29/2002
Bulk Current Injection Probe				
Narda /	769-6	02541	10/26/2001	10/25/2002
High Power Attenuator				

#### For Power Frequency Magnetic Field test :

	<b>,</b>			
Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
Haefely /	MAG 100.1	081436-02	No Calibration	No Calibration
Magic Field Tester			Required	Required
Extech Electronics /	CFC-105	810390	No Calibration	No Calibration
Frequency Converter			Required	Required
CHY/	932C	2K0900285	10/25/2001	10/24/2002
AC/DC Clamp Meter				

#### For Voltage Dips/Short Interruption and Voltage Variation Immunity test:

	1	0	, i i i i i i i i i i i i i i i i i i i	
Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
Haefely /	PLINE 1610	081568-06	08/06/2001	08/05/2002
Dips/Inerruption/Variations				
Tester				
FLUKE /	79-II	66400868	07/03/2001	07/02/2002
79 Series Ii Multimeter				

#### SECTION 1 EN 55022 (LINE CONDUCTED & RADIATED EMISSION)

## MEASUREMENT PROCEDURE (PRELIMINARY LINE CONDUCTED EMISSION TEST)

- The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- The EUT received DC 12V power through AC Adaptor and Line Impedance Stabilization Network (LISN) which supplied power source of 230VAC/ 50Hz and was grounded to the ground plane.
- 5) All support equipment received power from a second LISN supplying power of 110VAC/60Hz, if any.
- 6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- 7) Analyzer / Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- 8) During the above scans, the emissions were maximized by cable manipulation.
- 9) The following test mode were scanned during the preliminary test:

No.	Mode of operation	Date	Data Report/Plot No.
1	VGA Mode	03/12/2002	9999C#(52, 51)
2	VIDEO Mode	03/11/2002	99999C#(24, 32)

#### Mode(s):

10) After the preliminary scan, we found the following test mode producing the highest emission level.

#### Mode: 1.

Then, the EUT configuration and cable configuration of the above highest emission level were recorded for reference of final testing.

## **MEASUREMENT PROCEDURE** (FINAL LINE CONDUCTED EMISSION TEST)

1) EUT and support equipment was set up on the test bench as per step 10 of the preliminary test.

2) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the A.V. limit in Q.P. mode, then the emission signal was re-checked using an A.V. detector.

3) The test data of the worst case condition(s) was reported on the Summary Data page.

#### **Data Sample:**

	Meter		Corrected			Reading	
Freq	Reading	C.F.	Reading	Limits	Margin	Type	Line
(MHz)	(dBuV)	(dB)	(dBuV)	(dBuV)	(dB)	(P/Q/A)	(L1/L2)
X.XX	X.XX	X.XX	48.38	66.00	-17.62	Α	L1

C.F.(Correction Factor)=Insertion Loss + Cable Loss Corrected Reading = Metering Reading + C.F. Margin=Corrected Reading - Limits

P=Peak Reading	L1=Hot
Q=Quasi-peak	L2=Neutral
A=Average Reading	

Comments: N/A

## LINE CONDUCTED EMISSION LIMIT (EN 55022)

Frequency	Maximum RF Line Voltage		
	Q.P.	AVERAGE	
150kHz-500kHz	79dBuV	66dBuV	
500kHz-5MHz	73dBuV	60dBuV	
5MHz-30MHz	73dBuV	60dBuV	

Note: The lower limit shall apply at the transition frequency.

## MEASUREMENT PROCEDURE (COMMON MODE CONDUCTED EMISSION MEASUREMENT)

- 1) Selecting ISN for unscreened cable or a current probe for screened cable to take measurement.
- 2) The port of the EUT was connected to the remote side support equipment through the ISN/Current Probe and communication in normal condition.
- 3) Making a overall range scan by using the test receiver controlled by controller and record at least six highest emissions for showing in the test report.
- 4) Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit.
- 5) In case of measuring on the screened cable, the current limit shall be applied, otherwise the voltage limit should be applied.
- 6) The following test mode(s) were scanned during the preliminary test: Mode: N/A (EUT no any Telecommunicate Port)
- 7) After the preliminary scan, we found the following test mode(s) producing the highest emission level and test date of the worst case was reported on the summary data page. Mode: N/A

#### Data Sample:

Freq	Meter Reading	C.F.	Corrected Reading	Limits	Margin	Reading Type
(MHz)	(dBuV)	(dB)	(dBuV/m)	(dBuV/m)	(dB)	(P/Q/A)
X.XX	X.XX	X.XX	59.26	74.00	-14.74	Р

C.F.(Correction Factor)=Insertion Loss (9.5dB) + Cable Loss Corrected Reading = Metering Reading + C.F. Margin=Corrected Reading - Limits P=Peak Reading Q=Quasi-peak A=Aver

A=Average Reading

Comments: N/A

## COMMON MODE CONDUCTED EMISSION LIMIT AT TELECOMMUNICATION PORTS

CE-Mark (El	N 55022:1998)						
CLASS	Measuring	Measuring Voltage limit dB(uV) Current limit dB(uA)					
	Band	Q.P.	AV	Q.P.	AV		
D	150kHz-500kHz	84-74	74-64	40-30	30-20		
D	500kHz-30MHz	74	64	30	20		

**Note:** The lower limit shall apply at the transition frequency.

## MEASUREMENT PROCEDURE (PRELIMINARY RADIATED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- 4) The EUT received DC 12V power source from AC Adaptor (AC 230V/50Hz) to the outlet socket under the turntable. All support equipment received 110VAC/60Hz power from another socket under the turntable, if any.
- 5) The antenna was placed at 10 meter away from the EUT as stated in EN 55022. The antenna connected to the analyzer via a cable and at times a pre-amplifier would be used.
- 6) The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 7) The following test mode were scanned during the preliminary test:

#### Mode(s):

No.	Mode of operation	Date	Data Report/Plot No.
1	VGA Mode	03/11/2002	9999D#(01, 02)
2	VIDEO Mode	03/11/2002	9999D#(03, 04)

8) After the preliminary scan, we found the following test mode producing the highest emission level.

#### Mode: 1.

Then, the EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for final testing.

## MEASUREMENT PROCEDURE (FINAL RADIATED EMISSION TEST)

- 1) EUT and support equipment were set up on the turntable as per step 8 of the preliminary test.
- 2) The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 3) Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Peak reading is presented. If EUT emission level was less-2dB to the limit, then the emission signal was re-checked using a Q.P. detector.
- 4) The test data of the worst case condition(s) was reported on the Summary Data page.

#### **Data Sample:**

	Meter		Corrected			Reading	
Freq	Reading	C.F.	Reading	Limits	Margin	Type	Pol.
(MHz)	(dBuV)	(dB/m)	(dBuV/m)	(dBuV/m)	(dB)	P/Q/A	H/V
X.XX	X.XX	X.XX	40.82	47.00	-6.18	Р	V

C.F.(Correction Factor)=Antenna Factor + Cable Loss + Attenuator(6dB) - Amplifier Gain Corrected Reading = Metering Reading + C.F. Margin=Corrected Reading - Limits

P=Peak Reading	H=Horizontal Polarization/Antenna
Q=Quasi-peak	V=Vertical Polarization/Antenna
A=Average Reading	

Comments: N/A

## **RADIATED EMISSION LIMIT**

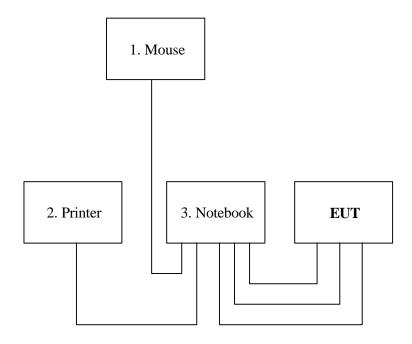
Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBu V/m/ Q.P.)
30-230	10	40
230-1000	10	47

Note: The lower limit shall apply at the transition frequency.

## **BLOCK DIAGRAM OF TEST SETUP**

#### System Diagram of Connections between EUT and Simulators

EUT: Industrial Display Monitor Trade Name: N/A Model Number: AMB-220A



## SUMMARY DATA (LINE CONDUCTED TEST)

Model Number: AMB-220A

Location: Conducted Room

Tested by: James Liao

Test Mode: Mode 1

Test Results: Passed

**Temperature:** 18

Humidity: 70%RH

(The chart below shows the highest readings taken from the final data)

Frequency Range Investigated			150 kHz TO 30 MHz				
	Meter		Corrected			Reading	
Freq	Reading	C.F.	Reading	Limits	Margin	Туре	Line
(MHz)	(dBuV)	(dB)	(dBuV)	(dBuV)	(dB)	(P/Q/A)	(L1/L2)
0.183	48.16	0.02	48.18	79.00	-30.82	Р	L1
0.505	41.51	0.05	41.56	73.00	-31.44	Р	L1
0.747	47.86	0.07	47.93	73.00	-25.07	Р	L1
2.622	41.35	0.16	41.51	73.00	-31.49	Р	L1
0.183	47.86	0.02	47.88	79.00	-31.12	Р	L2
2.500	38.66	0.16	38.82	73.00	-34.18	Р	L2

C.F.(Correction Factor)=Insertion Loss + Cable Loss

Corrected Reading = Metering Reading + C.F.

Margin=Corrected Reading - Limits

P=Peak Reading	L1=Hot
Q=Quasi-peak	L2=Neutral
A=Average Reading	

Comments: N/A

## SUMMARY DATA (RADIATED EMISSION TEST)

Model Number: AMB-220A

Tested by: James Liao

Test Mode: Mode 1

Test Results: Passed

Temperature: 18

Location: Site # D

Polar: Vertical / Horizontal- 10m

Humidity: 70%RH

(The chart below shows the highest readings taken from the final data)

	Frequency Range Investigated (30 MHz TO 1000 MHz)						
	Meter		Corrected			Reading	
Freq	Reading	C.F.	Reading	Limits	Margin	Туре	Pol.
(MHz)	(dBuV)	(dB/m)	(dBuV/m)	(dBuV/m)	(dB)	P/Q/A	H/V
120.156	40.49	-8.21	32.28	40.00	-7.72	Р	V
155.733	36.43	-5.31	31.12	40.00	-8.88	Р	V
120.133	39.73	-8.21	31.52	40.00	-8.48	Р	Н
155.733	40.39	-5.31	35.08	40.00	-4.92	Р	Н
180.189	36.30	-6.54	29.76	40.00	-10.24	Р	Н
204.600	43.51	-8.00	35.51	40.00	-4.49	Р	Н

C.F.(Correction Factor)=Antenna Factor + Cable Loss - Amplifier Gain (+ Attenuator 6dB)

Corrected Reading = Metering Reading + C.F.

Margin=Corrected Reading - Limits

- P=Peak Reading H=Horizontal Polarization/Antenna
- Q=Quasi-peak V=Vertical Polarization/Antenna

A=Average Reading

Comments: N/A

## SECTION 2 EN 61000-3-2 & EN 61000-3-3 (POWER HARMONICS & VOLTAGE FLUCTUATION / FLICKER)

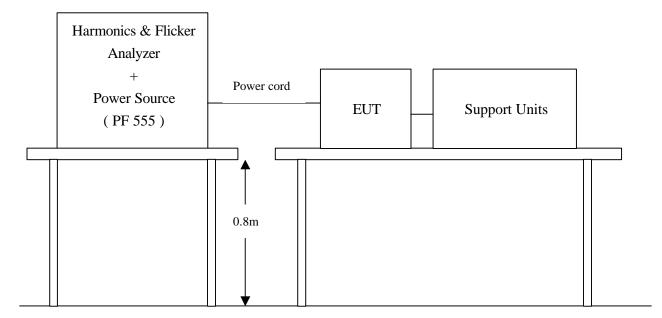
#### POWER HARMONICS MEASUREMENT

Port	: AC mains
<b>Basic Standard</b>	: EN 61000-3-2 (1995+A1: 1998+A2: 1998 + A14: 2000)
Limits	: Class A, V Class D
Temperature	$: 20^{\circ}$ C
Humidity	: 70%
Test By	: James Liao

#### **VOLTAGE FLUCTUATION/FLICKER MEASUREMENT**

Port	: AC mains
<b>Basic Standard</b>	: EN 61000-3-3 (1995)
Limits	: § 5 of EN 61000-3-3
Temperature	: 20 <sup>0</sup> C
Humidity	: 70%
Test By	: James Liao

#### **Block Diagram of Test Setup:**



#### **Result:**

Please see the attached test data.

Approved by:	ariung	_		
signature: Jam	5	Dat	te: ====================================	
Final Test Result: PASS				
Settings and Test Conditio	ons Compliant to th	e Standard: Ye	85	
Test Equipment Used:				
Agilent 6842A Harmoni HFTS Software Version Date Last Calibrated:	: A.05.03	tem with serial	number:	
Test Equipment Settings:				
Line Voltage: 230.00 V Line Prequency: 50 Hz Device Class: D RMS Current Limit: 13.1 P Peak Current Limit: 80.8 Number of Records: 5625	Measuremen Measuremen Quasi-sta	asurement Range it Window Type: it Delay: 10 se itionary Test Du rmination Pre-t	Rectangular	
Overrides: Test Limit Source (Power M Power Overrides: None Test Limit Overrides: None		tics): Maximum		
Pre-test Results for Class	Determination:			
Percent in Envelope: Class D Equipment?: Y	100.0% Voltage T es Fundamento	HD Out-of-Speci al Current: 0.	fication?: No 079 A	
RMS Voltage: 229.9 V Frequency: 50.0 Hz Voltage THD: 0.02% Maximum Power: 16.3 W	RMS Current: Peak Current: Current THD: Mean Power: 16	0.9 A 89.37%	Real Power: 16.3 W Apparent Power: 41.3 VA Power Factor: 0.396	
Active Power Statistics:				
100th Percentile: 16.3 W 90th Percentile: 16.3 W	99th Percentile 50th Percentile	: 16.3 W : 16.3 W	95th Percentile: 16.3	
fotal Number of Failures:	Tota	l Number of Err	ors:	
None		None		

Harmonic Number	Limit (%)	Limit (Volts)	Max (%)	Max (Volts)
Fund.	er de ver er pe de tot o		100.0	229.877
	0.20	0.460	0.005	0.012
2	0.90	2.069	0.006	0.013
-0	0.20	0.460	0.005	0.012
5	0.40	0.920	0.007	0.017
6	0.20	0.460	0.001	0.003
7	0.30	0.690	0.003	0.008
8	0.20	0.460	0.002	0.003
9	0.20	0.460	0.006	0.013
10	0.20	0.460	0.003	0.006
11	0.10	0.230	0.005	0.011
12	0.10	0.230	0.002	0.005
13	0.10	0.230	0.006	0.014
1.4	0.10	0.230	0.002	0.004
15	0.10	0.230	0.003	0.008
16	0.10	0.230	0.003	0.007
17	0.10	0.230	0.008	0.018
18	0.10	0.230	0.003	0.007
19	0.10	0.230	0.005	0.012
20	0.10	0.230	0.001	0.003
21	0.10	0.230	0.008	0.017
22	0.10	0.230	0.003	0.007
23	0.10	0.230	0.005	0.013
24	0.10	0.230	0.001	0.002
25	0.10	0.230	0.004	0.010
26	0.10	0.230	0.001	0.003
27	0.10	0.230	0.002	0.006
28	0.10	0.230	Q.001	0.001
29	0.10	0.230	0.005	0.011
3.0	0.10	0.230	0.003	0.006
3.2	0.10	0.230	0.001	0.003
32	0.10	0.230	0.001	0.002
33	0.10	0.230	0.002	0.004
3.4	0.10	0.230	0.001	0.001
35	0.10	0.230	0.002	0.004
36	0.10	0,230	0.003	0.006
37	0.10	0.230	0.003	0.006
38	0.10	0.230	0.002	0.004
3.9	0.10	0.230	0.004	0.009
40	0.10	0.230	0.001	0.002

Pre-Test Source Voltage Harmonics Data:

Final Test Data:

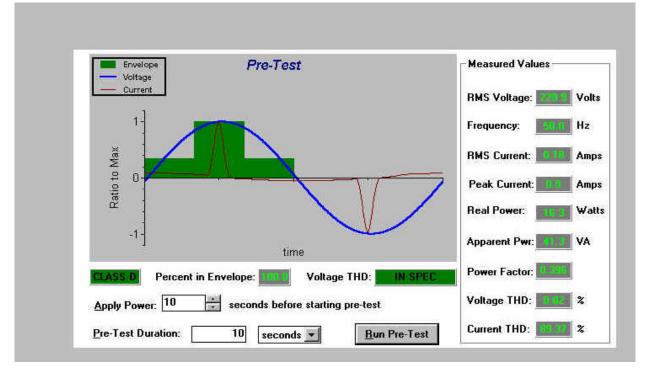
201000111100	Standard	Maximum	Maximum	Mean	Mean		Standard		(12)
Number	Limit (A rms)	Value (A rms)	Value (% Limit)	Value (A rms)	Value (% Limit)	(A rms)	Deviation (% Limit)	Fail	
Fund.	*********	0.0790		0.0765		0.0012	ne ang pangang ang ang ang ang ang ang ang ang		
2		0.0039		0.0032		0.0001			
з	2.3000	0.0674	2.9	0.0651	2.8	0.0012	0.1	P	
4		0.0020		0.0016		0.0001			
5	1.1400	0.0640	5.6	0.0619	5.4	0.0011	0.1	P.	
б		0,0015		0.0010		0.0001			
7	0.7700	0.0607	7.9	0.0589	7.7	0.0010	0.1	P	
8		0.0012		0.0009		0.0001			
9	0.4000	0.0575	14.4	0.0559	14.0	8000.0	0.2	P	
1.0		0.0012		0.0007		0.0001			
11	0.3300	0.0539	16.3	0.0524	15.9	0.0007	0.2	P	
12		0.0008		0.0004		0.0001			
13	0.2100	0.0493	23.5	0.0480	22.9	0.0006	0.3	P	
14		8000.0		0.0004		0.0001			
15	0.1500	0.0439	29.3	0.0430	28.7	0.0006	0.4	P	
16		0.0008		0.0004		0.0001			
17	0.1324	0.0390	29.5	0.0379	28.6	0.0007	0.6	P	
18		0.0007		0.0003	20110	0.0001		-	
19	0.1184	0.0342	28.9	0.0327	27.6	0.0009	0.8	P	
20		0,0006		0.0002		0.0001		11000	
21	0.1071	0.0293	27.4	0.0276	25.8	0.0011	1.0	P	
22		0.0006		0.0002		0.0001	0.000		
23	0.0978	0.0246	25.2	0.0228	23.3	0.0012	1.2	P	
24		0.0006		0.0002		0,0001			
25	0.0900	0,0201	22.4	0.0182	20.2	0.0012	1.4	P	
26		0.0007		0.0002		0.0001		11000	
27	0.0833	0.0161	19.3	0.0142	17.0	0.0012	1.4	P	
2.0		0.0007		0.0002		0.0001	1000	0.00	
29	0.0776	0.0126	16.2	0.0109	14.0	0.0011	1.4	P	
30		0,0007		0.0003		0.0001		100	
.31	0.0726	0.0097	13.4	0.0083	11.5	0.0008	1.2	P	
32		0.0007	10000	0.0003	10.00	0.0001		1.00	
33	0.0682	0.0077	11.3	0.0067	9.9	0.0005	0.7	P	
34	1.000	0.0007	1000	0.0003	0.505	0.0001	1444		
35	0.0643	0.0066	10.2	0.0061	9.4	0.0002	0.3	P	
36	- SSE 5.5-5-	0.0007	2012	0.0002		0.0001	0.000		
37	0.0608	0.0064	10.5	0.0059	9.7	0.0002	0.3	P	
38		0.0007		0.0003		0.0001			
3.9	0.0577	0.0066	11.4	0.0060	10.4	0.0002	0.4	P	
4.0	19.0.00 A.V.	0.0006	1. A A A A	0.0002		0.0001	1.4.4		

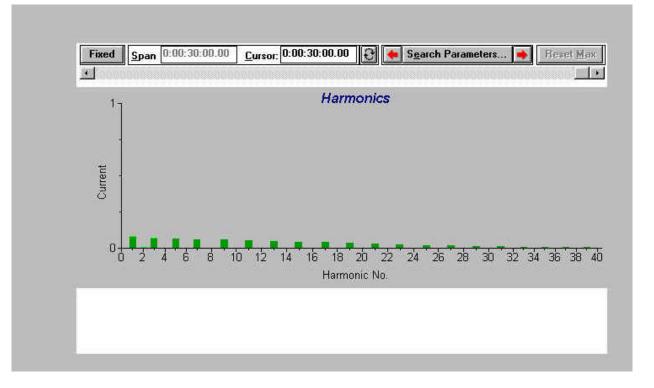
Final Test Statistics:

larmonic Number	Standard Limit (A rms)	Value (A rms)	Maximum Value (% Limit)	>50% of Limit (Count)	>75% of Limit (Count)	>90% of Limit (Count)	>95% of Limit (Count)	>100% of Limit (Count)	Pass(P) or Fail(F)
Fund.		0.0790				1 (15 No - 65 - 65) No - 56 - 59 No - 50 No		*****	10.00 (m) 10.00 (m) 10.00
2		0.0039		0	0	0	0	0	
3	2.3000	0.0674	2.9	0	0	0	0	0	P
4		0.0020		D	0	0	0	0	
5	1.1400	0.0640	5+6	0	0	0	0	0	tr.
6		0.0015		0	0	0	0	0	
7	0.7700	0.0607	7.9	D	0	0	0	0	12
8		0.0012		0	0	0	0	0	
9	0.4000	0.0575	14.4	0	0	0	0	0	P
10		0.0012		D	0	0	0	ő	
11	0.3300	0.0539	16.3	D	0	0	0	ő	p
12		0.0008	1. 1. 1. 1. 1.	0	0	0	0	ő	
13	0,2100	0.0493	23.5	0	0	0	0	õ	p.
14	1.000	0.0008	1000	D	õ	õ	0	ő	- A.
15	0.1500	0.0439	29.3	D	0	0	0	0	p
16	012000	0.0008		0	0	0	0	0	- 27
17	D.1324	0.0390	29.5	0	6	0	0	0	12
18	17 + 31 - 21 - 31	0.0007	- 60 P + 4	0	ŏ	0	0	0	-10°
19	0.1184	0.0342	28.9	0	0	0	0	0	-
20	N+TT04	0.0006	2.0 + 2	0		0			P
20	0,1071		22.4		0		0	0	1220
	0.10/1	0.0293	27.4	0	0	0	0	0	51
22		0.0006		0	0	0	0	0	
23	0.0978	0.0246	25.2	0	0	0	0	Û	P
24		0.0006	100	D	0	0	0	0	
25	0.0900	0.0201	22.4	D	0	0	0	0	Ŧ
26	1.1.1.1.2.2.1.1.1.2.1	0.0007	2201 121	0	0	0	0	0	
27	0,0833	0.0161	19.3	D	0	0	0	0	F
28		0.0007		Ð	0	0	0	0	
2.9	0.0776	0.0126	16.2	0	0	0	0	0	T5
30		0.0007		0	0	0	0	0	
31	0,0726	0.0097	13.4	0	0	0	0	0	분
32		0.0007		0	0	0	0	0	
33	0.0682	0.0077	11.3	D	0	0	0	0	$\Xi_{\beta}$
3.4		0.0007		0	0	0	0	0	
35	0.0643	0.0066	10.2	0	0	0	0	0	F
36		0.0007		0	0	0	0	0	
37	0.0608	0.0064	10.5	D	0	0	0	0	P
3.8		0.0007		Ð	0	0	0	0	
39	0.0577	0.0066	11.4	0	0	0	0	0	P
40		0.0006	120.000	0	0.	0	0	õ	117042

Remarks

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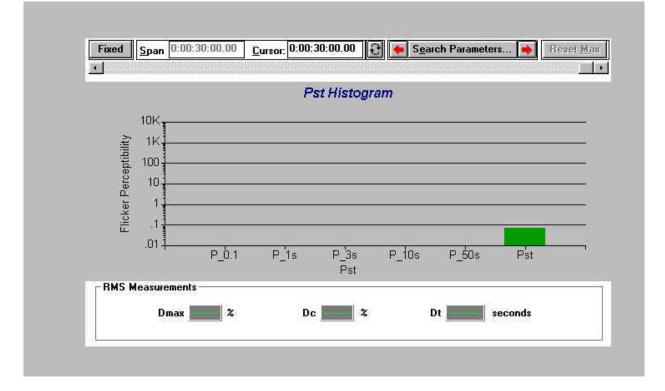


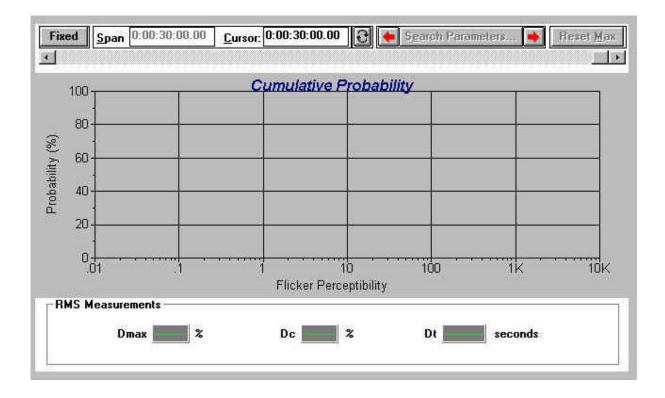
Approved by:	Vince	Chiang				
Signature:	J	imes		Da	ite: 3/	1.02
Final Test Re	sult: PASS					
Settings and	Test Conditions	Compliant t	o the Sta	ndard: Y	es	
Test Equipmer	nt Used:					
HFTS Sof	6842A Harmonic/ tware Version: t Calibrated:		System w:	ith seria	1 number:	
Test Equipmer						
Line Voltage: Line Frequenc Measurement I	230.00 V	onds		Pst In Duration:		
Overrides:						
	Limit Overrides t Overrides: No					
	ier Test Pre-te:					
RMS Voltage: Frequency: Voltage THD:	50.0 Hz		Current: Current: 90.08%		Power F	Real Power: 15.4 W Apparent Power: 40.8 VA actor: 0.377
Total Number	of Failures:			Total	Number of	Errors:
Pst: 0 Plt: 0	Dc: 0 Dmax: 0 Dt: 0				None	

	.0 .0 .00	E	st: 0.07 lt: 0.07 lt Thresho	ld: 0.65	P_0.1: P_1s: P_3s: P_10s: P_50s:	0.01 0.01 0.01				
Final Test	Data by	Integratio	on Period:							
Number of I Integration Periods		Period: ₽_0.1 (₽.U.)	P_1.0s (P.U.)	P_3.0s (P.U.)	P_10s (P.U.)	P_50s (P.U.)	Dc (%)	Dmax (%)	( Dt (seconds)	Pass(P) or Fail(E)

Remarks

Final Test Summary:



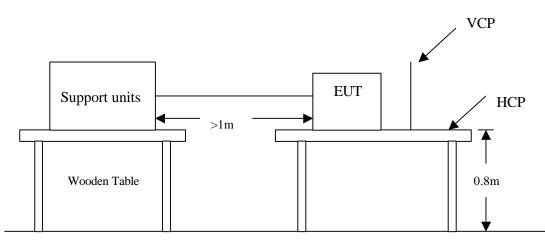


#### SECTION 3 IEC 61000-4-2 (ELECTROSTATIC DISCHARGE)

#### ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port	:	Enclosure
<b>Basic Standard</b>	:	IEC 61000-4-2
Requirements	:	±8 kV (Air Discharge)
		±4kV (Contact Discharge)
		±4kV (Indirect Discharge)
Performance Criteria	:	B (Standard require)
Temperature/Humidity	:	23°C /59%
Test By	:	Sam Hu

#### **Block Diagram of Test Setup:**



Ground Reference Plane

#### **Test Procedure:**

- 1. The EUT was located 0.1 m minimum from all side of the HCP.
- 2. The support units were located 1 m minimum away from the EUT.
- 3. A communication test program was loaded and executed in Windows mode.
- 4. PC sent transmit data to remote side via EUT.
- 5. As per the requirement of EN 55024; applying direct contact discharge at the sides other than front of EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.
- 6. Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.
- 7. The application of ESD to the contact of open connectors is not required.
- 8. Putting a mark on EUT to show tested points. The following test condition was followed during the tests.

Amount of	Voltage	Coupling	Result (Pass/Fail)
Discharges			
Mini 25 /Point	±4kV	Contact Discharge	Pass
Mini 25 /Point	±4kV	Indirect Discharge HCP (Front)	Pass
Mini 25 /Point	±4kV	Indirect Discharge VCP (Back)	Pass
Mini 25 /Point	±4kV	Indirect Discharge VCP (Left)	Pass
Mini 25 /Point	±4kV	Indirect Discharge VCP (Right)	Pass
Mini 10 /Point	±8kV	Air Discharge	Pass

The electrostatic discharges were applied as follows:

\*\* The tested points to EUT, please refer to attached page.

(Blue arrow mark for contact discharge, red arrow mark for air discharge.)

#### Performance & Result:

- V Criteria A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

**Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

V PASS	FAILED
--------	--------

## **Observation: No any function degraded during the tests.**

The Tested Points of EUT

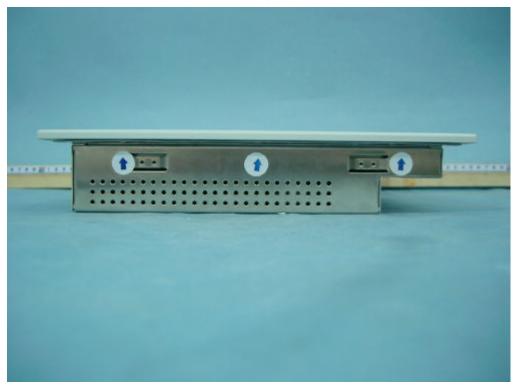


(*Photo 1 of 6*)

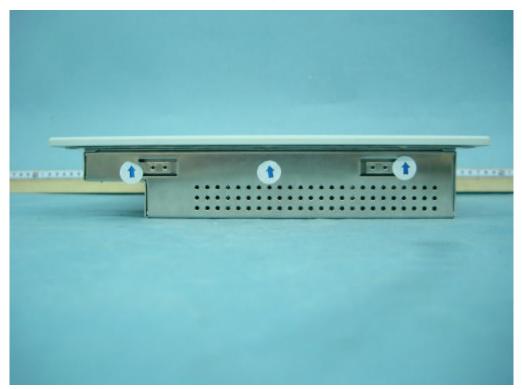
(*Photo 2 of 6*)



### (*Photo 3 of 6*)



#### (*Photo 4 of 6*)



### (*Photo 5 of 6*)



#### (*Photo6 of 6*)

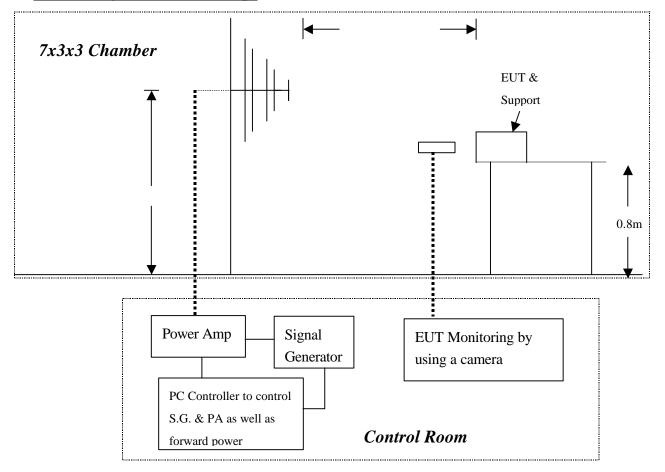


### SECTION 4 IEC 61000-4-3 (RADIATED ELECTROMAGNETIC FIELD )

#### **RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST**

Port	: Enclosure
<b>Basic Standard</b>	: IEC 61000-4-3
Requirements	: 3 V/m / with 80% AM. 1kHz Modulation
Performance Criteria	: A (Standard require)
Tester	: Sam Hu
Temperature	: 24
Humidity	: 55%
Note	: The EUT not have acoustic interfaces, the annex A of EN 55024
	should not be applied.

#### **Block Diagram of Test Setup:**



#### **Test Procedure:**

- 1. The EUT and support units were located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity.
- 2. Adjusting the cables to be exposed to the electromagnetic filed as possible.
- 3. Performing a Radiated Emission Scan in range of 30 to 1000 MHz prior to do RS test and records the more higher emission frequencies for the reference of RS test, due to antenna effectiveness.
- 4. Adjusting the monitoring camera to monitor the "H" message as clear as possible.
- 5. Setting the testing parameters of RS test software per IEC 61000-4-3.
- 6. Referring to the tested data of step 3 to performing the RS test from 80 to 1000 MHz.
- 7. Recording the test result in following table.
- 8. Changing the EUT to the other side and repeat step 3 to 6, until 4 sides of EUT were verified.

Test level	: 3V/m					
Steps	: 1 % of fundamental					
Dwell Time	: 3 sec					
Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)	
80-1000	3V	Yes	Н	Front	Pass	
80-1000	3V	Yes	V	Front	Pass	
80-1000	3V	Yes	Н	Right	Pass	
80-1000	3V	Yes	V	Right	Pass	
80-1000	3V	Yes	Н	Back	Pass	
80-1000	3V	Yes	V	Back	Pass	
80-1000	3V	Yes	Н	Left	Pass	
80-1000	3V	Yes	V	Left	Pass	

#### IEC 61000-4-3 Final test conditions:

#### Performance & Result:

- V Criteria A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
  - **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

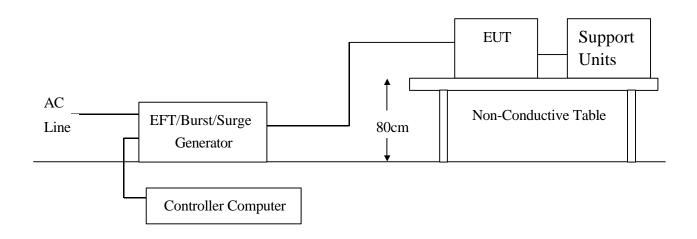
V PASS FAILED
Observation: No any function degraded during the tests.

## SECTION 5 IEC 61000-4-4 (FAST TRANSIENTS/BURST)

### FAST TRANSIENTS/BURST IMMUNITY TEST

Port	: On Power Lines
<b>Basic Standard</b>	: IEC 61000-4-4
Requirements	: ±1kV for Power Supply Lines
Performance Criteria	: B (Standard require)
Temperature	: 23 <sup>0</sup> C
Humidity	: 59%
Test By	: Sam Hu

#### **Block Diagram of Test Setup:**



#### **Test Procedure:**

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground reference plane.
- 2. A 1.0 meter long power cord was attached to EUT during the test.
- 3. The length of communication cable between communication port and clamp was keeping within 1 meter.
- 4. A test program was loaded and executed in Windows mode.
- 5. The data was display on the monitor and filling the screens.
- 6. The test program exercised related support units sequentially.
- 7. Repeating step 3 to 6 through the test.
- 8. Recording the test result as shown in following table.

#### **Test conditions:**

Impulse Frequency: 5kHz Tr/Th: 5/50ns Burst Duration: 15ms Burst Period: 300mS

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L1	+/- 1	Direct	Pass
Ν	+/- 1	Direct	Pass
PE	+/- 1	Direct	Pass
L1+N	+/- 1	Direct	Pass
L1+PE	+/- 1	Direct	Pass
N+PE	+/- 1	Direct	Pass
L1+N+PE	+/- 1	Direct	Pass

#### Performance & Result:

- V Criteria A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

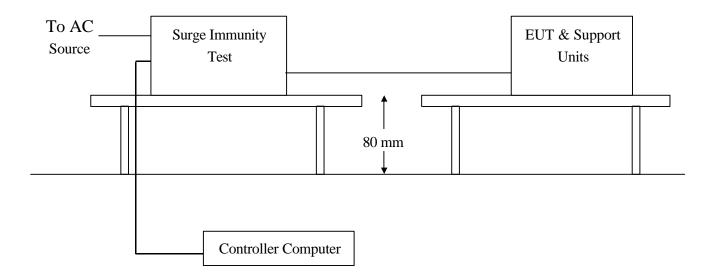
V PASS	<b>FAILED</b>
<b>Observation: No any function d</b>	legraded during the tests.

### SECTION 6 IEC 61000-4-5 (SURGE IMMUNITY)

### SURGE IMMUNITY TEST

Port	:	Power Cord
<b>Basic Standard</b>	:	IEC 61000-4-5
Requirements	:	+/- 1kV (Line to Line of Power Port)
		+/- 2kV (Line to Earth of Power Port)
Performance Criteria	:	B (Standard require)
Temperature	:	23
Humidity	:	59%
Test By	:	Sam Hu

## **Block Diagram of Test Setup:**



#### **Test Procedure:**

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground floor.
- 2. A test program was loaded and executed in Windows mode.
- 3. The data was display on the monitor and filling the screens.
- 4. The test program exercised related support units sequentially.
- 5. Repeating step 3 to 4 through the test.
- 6. Recording the test result as shown in following table.

#### Test conditions:

Voltage Waveform	: 1.2/50 us
Current Waveform	: 8/20 us
Polarity	: Positive/Negative
Phase angle	: 0°, 90°, 270°
Number of Test	: 5

Coupling Line	Voltage (kV)	Polarity	<b>Coupling Method</b>	Result (Pass/Fail)
L1-L2、L1-PE、L2-PE	1	Positive	Capacitive	Pass
L1-L2、L1-PE、L2-PE	1	Negative	Capacitive	Pass
L1-PE、L2-PE	2	Positive	Capacitive	Pass
L1-PE、L2-PE	2	Negative	Capacitive	Pass

### Performance & Result:

- V Criteria A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
  - **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

V PASS	<b>FAILED</b>
<b>Observation: No any function</b>	degraded during the tests.

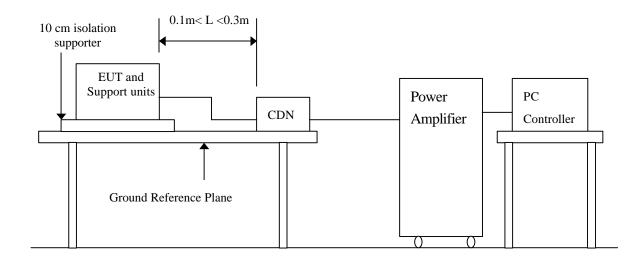
## SECTION 7 IEC 61000-4-6 (CONDUCTED DISTRBANCE/INDUCED BY RADIO-FREQUENCY FIELD)

#### CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS

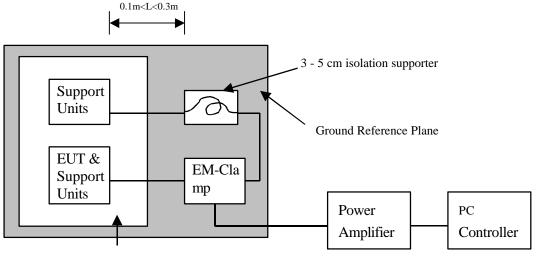
Port	: AC Port
<b>Basic Standard</b>	: IEC 61000-4-6
Requirements	: 3V with 80% AM. Modulation
Injection Method	: CDN-M2
Performance Criteria	: A (Standard require)
Temperature	: 24 <sup>0</sup> C
Humidity	: 55%
Test By	: Sam Hu

#### **Block Diagram of Test Setup:**

#### Side view:



#### **Top view:**



10 cm isolation supporter

### **Test Procedure:**

- 1. The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- 2. Transmit data messages were displayed on screen of Monitor.
- 3. Adjusting the monitoring camera to monitor the transmit data message as clear as possible.
- 4. Setting the testing parameters of CS test software per EN 61000-4-6.
- 5. Recording the test result in following table.

#### **Test conditions:**

Frequency Range	: 0.15MHz-80MHz
Frequency Step	: 1% of fundamental
Dwell Time	: 3 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	3V	Yes	Pass

#### Performance & Result:

- **V** Criteria A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
  - **Criteria C:** Temporary loss of function is allowed, provided the functions self-recoverable or can be restored by the operation of controls.

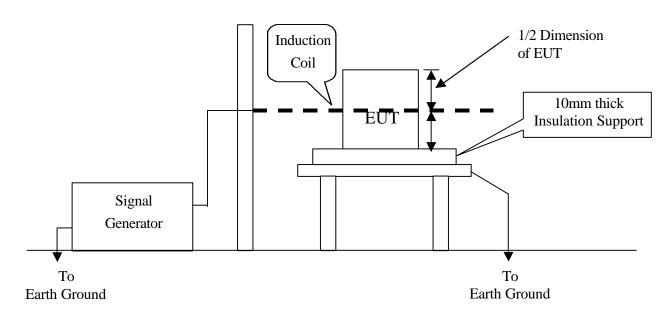
V PASS	<b>FAILED</b>
<b>Observation:</b> No any function	degraded during the tests.

### SECTION 8 IEC 61000-4-8 (POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST)

### POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST

Port	: Enclosure
<b>Basic Standard</b>	: IEC 61000-4-8
Requirements	<b>:</b> 1 A/m
Performance Criteria	: A (Standard Required)
Temperature	: N/A
Humidity	: N/A
Test By	: N/A

### **Block Diagram of Test Setup:**



#### **Test Procedure:**

- 1. The EUT and support units were located on Ground Reference Plane with the interposition of a 0.1 m thickness insulation support.
- 2. Putting the induction coil on horizontal direction.( X direction )
- 3. A test program was loaded and executed in Windows mode.
- 4. The data was sent to the screen of EUT and filling the screen with upper case of "H" patterns.
- 5. The test program exercised related support units sequentially.
- 6. Repeating step 3 to 5 through the test.
- 7. Recording the test result as shown in following table.
- 8. Rotating the induction coil by  $90^{\circ}$  (Y direction) then repeat step 3 to 7.
- 9. Rotating the induction coil by  $90^{\circ}$  again (Z direction) then repeat step 3 to 7.

\*. Test conditions:

Field Strength:	1A/m
Power Freq.:	50Hz
Orientation:	X, Y, Z

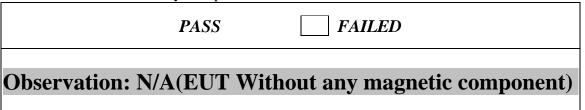
Orientation	Field	Result (Pass/Fail)	Remark

\*\*Note: Not applicable, because no any component can be influenced by power magnetic fields.

#### Performance & Result:

- **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

**Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.



## SECTION 9 IEC 61000-4-11 (VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS )

### **VOLTAGE DIPS / SHORT INTERRUPTIONS**

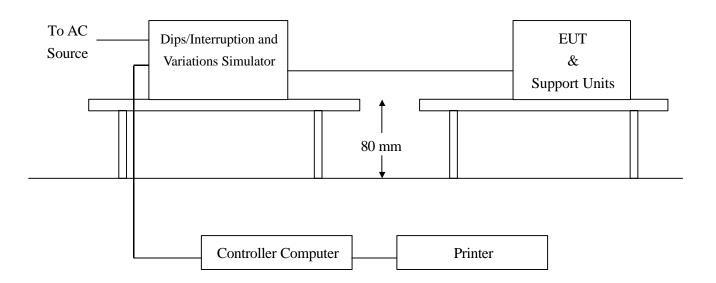
Port	: AC mains
<b>Basic Standard</b>	: IEC 61000-4-11 (1994)
Requirement	: PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

Voltage	Test Level % U <sub>T</sub>	Reduction (%)	Duration ( periods )	Performance Criteria
Dips	<5	>95	0.5	В
	70	30	25	С
	-			
	Track Lange 1	Deduction	Dermettern	Deufeure

Voltage Test Level   Intercentions % U <sub>T</sub>	Reduction (%)	Duration ( periods )	Performance Criteria	
Interceptions	<5	>95	250	С

Test Interval	: Min. 10 sec.
Temperature	: 23 <sup>0</sup> C
Humidity	: 59%
Test By	: Sam Hu

## **Block Diagram of Test Setup:**



#### **Test Procedure:**

- 1. The EUT and support units were located on a wooden table, 0.8 m away from ground floor.
- 2. A test program was loaded and executed in Windows mode.
- 3. The data was displayed on the monitor and filling the screens.
- 4. The test program exercised related support units sequentially.
- 5. Setting the parameter of tests and then Perform the test software of test simulator.
- 6. Conditions changes to occur at 0 degree crossover point of the voltage waveform.
- 7. Repeating step 3 to 4 through the test.
- 8. Recording the test result in test record form.

#### **Test conditions:**

The duration with a sequence of three dips/interruptions with interval of 10s minimum (between each test events)

#### Voltage Dips:

Test Level % U <sub>T</sub>	Reduction (%)	Duration ( periods)	Observation	Meet Performance Criteria
0	100	0.5	Normal	А
70	30	25	Normal	А

#### **Voltage Interruptions:**

Test Level	Reduction	Duration	Observation	Meet Performance
% U <sub>T</sub>	(%)	(periods)		Criteria
0	100	250	EUT shut down, But EUT	С
			can be auto recovered after	
			EUT restart.	

Normal: No any functions degrade during and after the test.

#### Performance & Result:

- **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.



# **APPENDIX 1**

# **PHOTOGRAPHS OF TEST SETUP**



## LINE CONDUCTED EMISSION TEST (EN 55022)





### **RADIATED EMISSION TEST (EN 55022)**



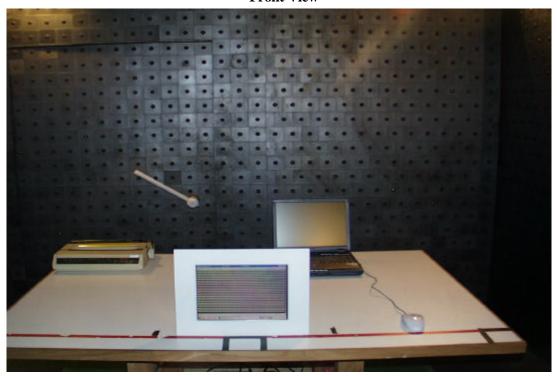
# POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST (EN 61000-3-2, EN 61000-3-3)



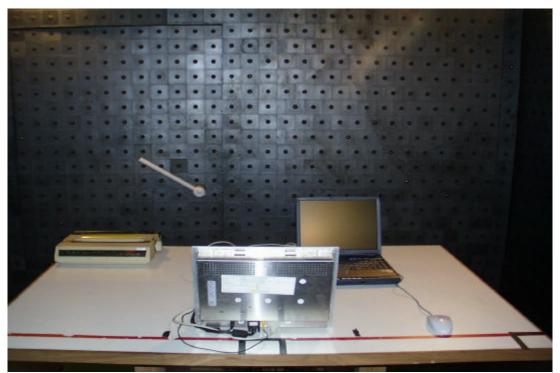


# ELECTROSTATIC DISCHARGE TEST (IEC 61000-4-2)

### RADIATED ELECTROMAGNETIC FIELD (IEC 61000-4-3) Front View



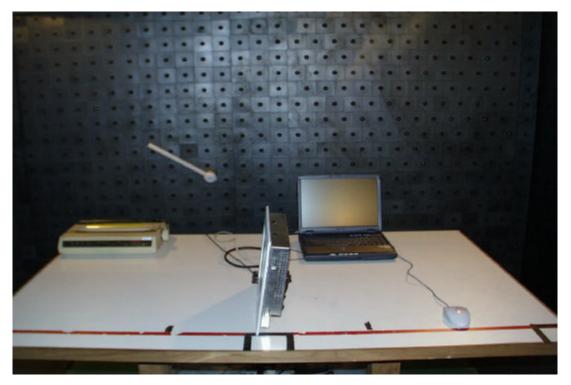
**Back View** 



**Right View** 



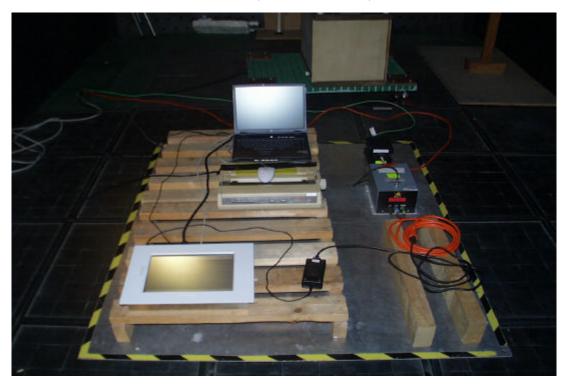
Left View



## FAST TRANSIENTS/BURST TEST & SURGE IMMUNITY TEST (IEC 61000-4-4/5)



## CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST (IEC 61000-4-6)



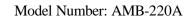


# **VOLTAGE DIPS / INTERRUPTION TEST (IEC 61000-4-11)**

Report Number: 02E9999-E March 20, 2002

# **APPENDIX 2**

# **PHOTOGRAPHS OF EUT**















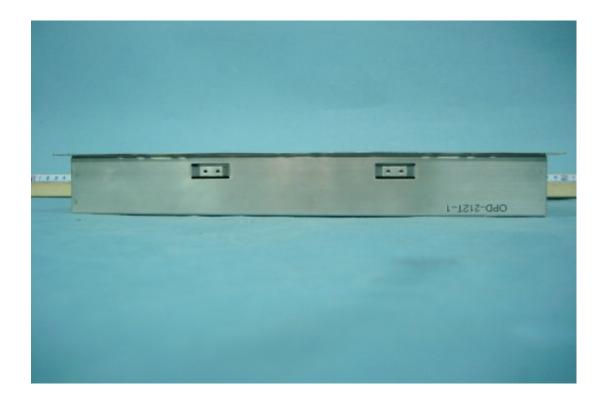
Model Number: OPD-212A













### Cable & Adaptor







Report Number: 02E9999-E March 20, 2002

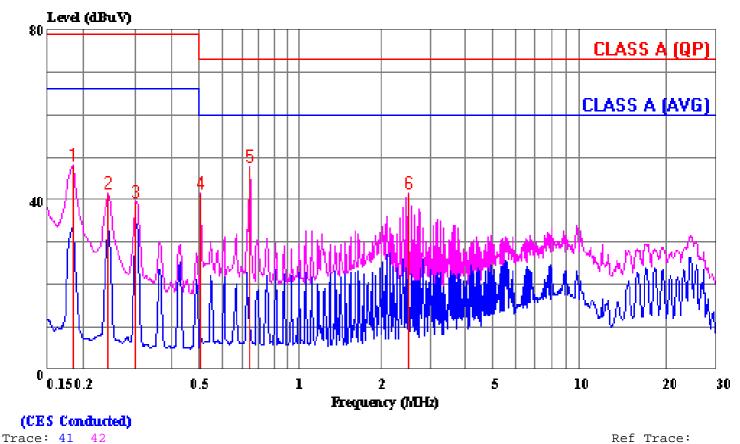
## **APPENDIX 3**

# CONDUCTED EMISSION PLOT RADIATED EMISSION DATA



#### Data#: 52 File#: 9999c.EMI

Date: 2002-03-12 Time: 10:03:14



Ref Trace:

Condition: LI	NE
Report No. :	02E9999
Test Engr. :	JAMES LIAO
Company :	AAEON Technology Inc.
EUT :	AMB-220A
Test Config :	EUT/ ALL PERIPHERALS
Type of Test:	EN 55022 CLASS A

Mode of Op. : VGA MODE (WORST)

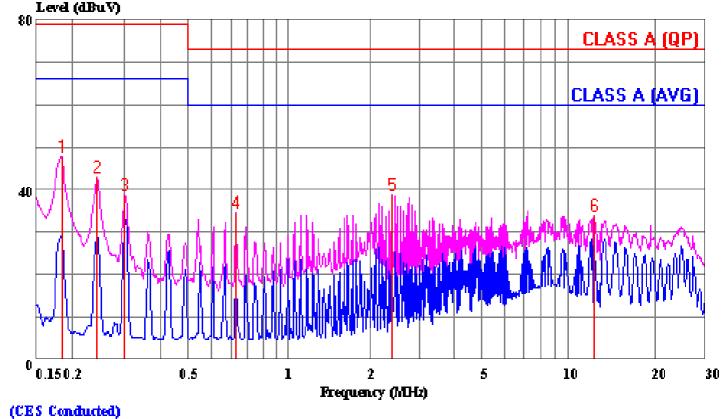
	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark
-	MHz	dBuV	dB	dBuV	dBuV	dB	
1 2 3 4 5 6		48.16 41.38 39.57 41.51 47.86 41.35	0.02 0.02 0.02 0.05 0.07 0.16		79.00 79.00 73.00 73.00	-30.82 -37.60 -39.41 -31.44 -25.07 -31.49	Peak Peak Peak Peak



#### Data#: 51 File#: 9999c.EMI

No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C. Tel:02-2217-0894 Fax:02-2217-1254

Date: 2002-03-12 Time: 10:01:34



Ref Trace:

Trace: 49 50

Condition: NEUTRAL Report No. : 02E9999 Test Engr. : JAMES LIAO Company : AAEON Technology Inc. EUT : AMB-220A Test Config : EUT/ ALL PERIPHERALS Type of Test: EN 55022 CLASS A Mode of Op. : VGA MODE (WORST)

	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	
1 2 3 4 5 6	0.183 0.243 0.302 0.724 2.500 12.384	47.86 42.92 38.76 34.47 38.66 33.56	0.02 0.02 0.02 0.07 0.16 0.37	38.78 34.54	79.00 79.00 73.00 73.00	-31.12 -36.06 -40.22 -38.46 -34.18 -39.07	Peak Peak Peak Peak



No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C. Tel:02-2217-0894 Fax:02-2217-1254

Date: 2002-03-11 Time: 18:08:15

Data#: 1 File#: 9999d.EMI D-Site

Condition: VERTICAL / 10m Report No. : 02E9999 Test Engr. : JAMES LIAO Company : AAEON Technology Inc. EUT : AMB-220A Test Config : EUT/ALL PERIPHERALS Type of Test: EN 55022 CLASS A Mode of Op. : VGA MODE (WORST)

	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark
	MHz	dBuV	dB	$\overline{dBuV/m}$	$\overline{dBuV/m}$	dB	
1 2 3 4 5 6 7 8	120.156 155.733 180.222 204.622 240.622 263.845 295.933 325.711	40.49 36.43 36.15 36.18 38.44 38.05 34.75 37.83	-8.21 -5.31 -6.54 -8.00 -6.48 -5.83 -4.88 -4.09	32.28 31.12 29.61 28.18 31.96 32.22 29.87 33.74	40.00 47.00 47.00 47.00		Peak Peak Peak Peak Peak Peak



No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C. Tel:02-2217-0894 Fax:02-2217-1254

Date: 2002-03-11 Time: 18:18:22

Data#: 2 File#: 9999d.EMI D-Site

Condition: HORIZONTAL / 10m Report No. : 02E9999 Test Engr. : JAMES LIAO Company : AAEON Technology Inc. EUT : AMB-220A Test Config : EUT/ALL PERIPHERALS Type of Test: EN 55022 CLASS A Mode of Op. : VGA MODE (WORTS)

	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark
	MHz	dBuV		dBuV/m	dBuV/m	dB	
1 2 3 4 5 6 7 8	120.133 155.733 180.189 204.600 240.494 263.583 295.911 325.722	39.73 40.39 36.30 43.51 39.17 38.31 35.49 38.87	-8.21 -5.31 -6.54 -8.00 -6.48 -5.87 -4.88 -4.09	31.52 35.08 29.76 35.51 32.69 32.44 30.61 34.78	40.00 40.00 47.00 47.00 47.00	-8.48 -4.92 -10.24 -4.49 -14.31 -14.56 -16.39 -12.22	Peak Peak Peak Peak Peak Peak